PAIDC

Application No. 09/854,905 Prepared by N.H. Tracking Number 05883687

Examiner-GAU Port - 2829 Date 2-2-04 Week Date 01-05-04

No. of queries 1

JACKET						
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449			
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b			
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract			
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs			
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other			

SPECIFICATION	MESSAGE
a. Page Missing	PTO-1449: Please either initial or line
b. Text Continuity	through citations. Copies provided for
c. Holes through Data	reference
d. Other Missing Text	
e. Illegible Text	
f. Duplicate Text	
g. Brief Description	
h. Sequence Listing	
i. Appendix	
j. Amendments	
k. Other	
CLAIMS	
a. Claim(s) Missing	
b. Improper Dependency	Phankyon
c. Duplicate Numbers	
d. Incorrect Numbering	initials N.H.
e. Index Disagrees	RESPONSE
f. Punctuation	
g. Amendments	
h. Bracketing	
i. Missing Text	
j. Duplicate Text	
k. Other	
	initials





	25.0	OFFIC					Sheet 1 of 2
FORM PTO-144	9 U.S. DEPARTM	IENT ÓF (COMMERCE	ATT	Y. DOCKET NO	D. SE	ERIAL NO.
	PATENT AND	ARK OFFICE					
· IN	IFORMATION DIS		11157-23		09	09/854,905	
			APPLICANT				
	(Use several	sheets If r	ecessary)	200	N. MOODE	•	
				BRIAN MOORE			
				FILING DATE		G	ROUP
							•
				May	15, 2001	28	358
			U.S. PATENT DOCL	JMENTS			
EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLA	SS FILING DATE
NITIALS		00/05/72	Vanian et al		340	152T	09/15/70
	3,689,885	01/11/77	Kaplan et al.		324	73 R	11/13/75
	4,002,974 4,105,950	08/08/78			331	57	09/12/77
	4,517,532	05/14/85			331	57	07/01/83
	4,985,681		Brunner et al.		324	501	12/27/85
	5,030,908	-	Miyoshi et al.		324	158 R	01/23/
	5,039,602		Merrill et al.		437	8	03/19/9
	5,059,899		Farnworth et al.		324	158 R	08/16/5
	5,068,521	 	Yamaguchi		235	492	08/16/8
	5,113,184	 	Katayama		340	825.54	05/20/9
	5,149,662	 	Eichelberger		437	8	02/21/9
	5,192,913	+	Goruganthu et al.		324	537	03/16/9
	5,252,914	<u> </u>	Bobbitt et al.		324	158 F	05/07/9
	5,266,890	1	Kumbasar et ål.		324	158 R	06/26/9:
- 	5,279,975	01/18/94	Devereaux et al.		437	8	02/07/9:
	5,315,241	05/24/94	Ewers	 	324	158 R	09/18/91
	5,365,204	11/15/94	Angiulli et al.		331	57	10/29/93
	5,457,400	10/10/95	Ahmad et al.		324	763	07/23/93
	5,619,463	04/08/97	Malhi		365	201	08/24/95
	5,625,288	04/29/97	Snyder et al.		324	158.1	01/16/96
	5,714,888	02/03/98	Naujoks		324	750	12/26/95
	5,790,479	08/04/98	Conn		368	118	09/17/96
	5,811,983	09/22/98	Lundberg	0	324	763	09/03/96
	5,818,250	10/06/98	Yeung et al.		324	763	07/03/96
	5,867,033	02/02/99	Sporck et al.		324	763	05/24/96
	5,892,368	04/06/99	Nakata et al.		324	763	11/04/96
	5,905,383	05/18/99	Frisch		324	765	08/29/95
	5,923,676	07/13/99	Sunter et al.		371	22.5	12/20/96
	5,952,840		Farnworth et al.		324	755	12/31/96
	5,983,363	11/09/99	Tuttle et al.		714	25	09/15/94

/	61	-	Į	2 30		
	SEP	0	4	2001	ريز زيز	

09/854,905

	1 /14	יו אינטען אינו	<u> </u>			
				324	765 ' '	12/19/97
	5,995,428			365	201	02/27/98
		2/07/99 N		324	765	07/25/97
	1010001	12/21/99 A		324	765	10/23/95
	1-1	12/21/99 C		368	118	05/21/98
+	0,000,	05/02/00		714	733	11/20/92
	10,000,000		Cheek et al.	331	44	01/05/98
+	1-1		Parker et al.	324	763	04/29/96
			Parker et al.	324	763	05/06/98
		09/12/00		714	724	01/21/98
	1 1 1 1 1 1 1 1		Osann, Jr. et al.	257		05/14/98
		10/17/00		368	118	02/26/99
				714	724	11/16/98
*		12/12/00		331	57	05/05/99
	-1111		Schoellkopf	365	201	05/24/99
			Nam et al.	324	750	03/23/98
			White et al.	714	724	02/29/00
-		02/13/01		368	113	07/14/98
	6,219,305		Patrie et al.	714	726	12/31/97
	6,223,314		Arabi et al.	324	765	02/10/99
	6,236,223		Brady et al.	324	158.1	04/29/99
	6,239,591		Bryant et al.		763	06/23/99
	6,239,603		Ukei et al.	324	/03	00123133
			IGN PATENT DOCUMENTS	T 01 4 00	SUBCLASS	TRANSLATIO
	DOCUMENT		COUNTRY	CLASS		Not needed
ν	0098399	06/04/86		G 01 R 31	28	
	0911640	04/28/99	Europe	G 01R 29	027	Not needed
	99/16107	04/01/99	PCT	H01L	-	Not needed
`	99/32893	07/01/99	PCT	G01R 31	00	Not needed
١	99/65287	12/23/99	PCT	N/a	N/a	Not needed
	OTHER DOCUM	ENTS (Inc	luding Author, Title, Date, Pertin	ent Pages, etc.)		
troduction to	Component Testin	ng - by An	thony K. Stevens – 1986 – pages 3	-14 & pages 91-	119	

Introduction to Component Testing - by Anthony K. Stevens - 1986 - pages 3-14 & page

Semiconductor Material and Device Characterization – by Dieter K. Schroder – 1990 – pages 1-40

CMOS Digital Integrated Circuits - by Sung-Mo (Steve) Kang & Yusuf Leblebici - 1999 - pages 220-242, Chaps 6, 9, 11, 15

A Self-Tuning Digital Telemetry IC for Use in a Microprocessor-Based Implantable Instrument – IEEE Journal of Solid-State Curcuits – Vol. 27, No 12 (Dec. 1992) - by Kenneth W. Fernald, John J. Paulos, Blaine A. Stackhouse & Robert A. Heaton – Pages 1826-1832

Testing the Monster Chip - IEEE Spectrum, (July 1999) - by Yervant Zorian - Pages 54-60

EXAMINER:

DATE CONSIDERED

*EXAMINER: Initial if citation not considered, whether or not citation is in conformance with MPEP 609;draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



PTO/SB/08A (10-01)
Approved for use through 10/31/2002. OMB 0651-0031
U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO					C mplet if Known		
					Application Number	09/854,905	
				CLOSURE	Filing Date	May 15, 2001	
S	STATEMENT BY APPLICANT			PPLICANT	First Named Inventor	MOORE, Brian	
			Group Art Unit	2829			
	(1	use as manv	sheets as	necessary)	Examiner Name	N/A	
	heet	1	of	[1	Attorney Docket Number	11157-23	

	OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS					
Examiner	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue					
am/		K. ARABI et al. "Digital Oscillation-Test Method for Delay and Stuck-at-Fault Testing of Digital Circuits", International Test Conference, 1998, pp. 91-98.				
· · · · · · · · · · · · · · · · · · ·						
 						
	 					
	-					
	+					

Examiner Signature	Vimmy Naugen	Date Considered	6/4/03	

EXAMINER: Initial if reference considered, whether of not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.

¹ Unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.